

Please add the following new claims:

--9. (New) An interferometric measuring device for measuring shape, including surfaces of a measured object, comprising:

- a radiation-producing unit emitting short-coherent radiation;
- a beam splitter for forming a first beam component and a second beam component, wherein the first beam component is directed via an object light path to the measured object and the second beam component is directed via a reference light path to a reflecting reference plane;
- a superposition element at which a radiation coming from the measured object and a radiation coming from the reflecting reference plane are brought to superposition;
- an image converter which receives the superposed radiation and sends corresponding signals to a device for evaluation, wherein, for the measurement, an optical path length of the object light path is changed relative to an optical path length of the reference light path; and
- an optical probe including an optical device for generating at least one optical intermediate image, wherein the optical probe is provided in the object light path.

10. (New) The measuring device according to claim 9, wherein the at least one intermediate image is generated in the object light path.

11. (New) The measuring device according to claim 10, wherein both the radiation directed to the measured object and the radiation returning from the measured object pass through the optical probe.

12. (New) The measuring device according to claim 9, further comprising, in the reference light path, one of a further optical probe and a glass device for compensating for a glass proportion present in the optical probe with regard to the elements for the intermediate image.

13. (New) The measuring device according to claim 9, wherein the first beam component formed by the beam splitter is first directed via a first arm to a fixed first mirror;

wherein the second beam component is directed via a second arm to the reflecting element;

At
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